





DRV5013 SLIS150L - MARCH 2014 - REVISED FEBRUARY 2023

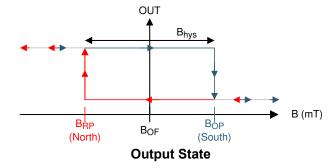
DRV5013 Digital-Latch Hall Effect Sensor

1 Features

- Digital bipolar-latch Hall sensor
- Superior temperature stability
 - B_{OP} ±10% over temperature
- Multiple sensitivity options (B_{OP} / B_{RP})
 - ±1.3 mT (FA, see Device Nomenclature)
 - ±2.7 mT (AD, see Device Nomenclature)
 - ±6 mT (AG, see Device Nomenclature)
 - ±12 mT (BC, see Device Nomenclature)
- Supports a wide voltage range
 - 2.5 V to 38 V
 - No external regulator required
- · Wide operating temperature range
 - T_A = -40 to +125°C (Q, see *Device* Nomenclature)
 - T_A = -40 to +150°C (E, see *Device* Nomenclature)
- Open-drain output (30-mA sink)
- Fast 35-µs power-on time
- Small package and footprint
 - Surface mount 3-pin SOT-23 (DBZ)
 - 2.92 mm × 2.37 mm
 - Through-hole 3-pin TO-92 (LPG, LPE)
 - 4.00 mm × 3.15 mm

Protection features:

- Reverse supply protection (up to –22 V)
- Supports up to 40-V load dump
- Output short-circuit protection
- Output current limitation



2 Applications

- Power tools
- Flow meters
- Valve and solenoid status
- Brushless dc motors
- Proximity sensing
- **Tachometers**

3 Description

The DRV5013 device is a chopper-stabilized Hall effect sensor that offers a magnetic sensing solution with superior sensitivity stability over temperature and integrated protection features.

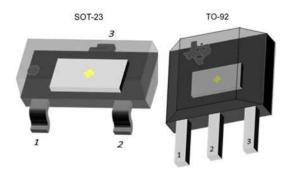
The magnetic field is indicated through a digital bipolar latch output. The IC has an open-drain output stage with 30-mA current sink capability. A wide operating voltage range from 2.5 V to 38 V with reverse polarity protection up to -22 V makes the device suitable for a wide range of industrial applications.

Internal protection functions are provided for reverse supply conditions, load dump, and output short circuit or overcurrent.

Package Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)			
DRV5013	SOT-23 (3)	2.92 mm × 1.30 mm			
DIXV3013	TO-92 (3)	4.00 mm × 3.15 mm			

For all available packages, see the package option addendum at the end of the data sheet.



Device Packages



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Changes from Revision F (May 2016) to Revision G (August 2016) Changed the maximum B_{OP} and the minimum B_{RP} for the FA version in the Magnetic Characteristics table.... Changes from Revision E (February 2016) to Revision F (May 2016) Changes from Revision D (December 2015) to Revision E (February 2016) Page Added the FA device option......1 Changes from Revision C (September 2014) to Revision D (June 2015) Added B_{MAX} to Absolute Maximum Ratings5 Removed table note from junction temperature5 Changes from Revision B (July 2014) to Revision C (September 2014) Updated the output rise and fall time typical values and removed max values in Switching Characteristics 6 Updated all Typical Characteristics graphs8 Changes from Revision A (March 2014) to Revision B (June 2014) Page Changed I_{OCP} MIN and MAX values from 20 and 40 to 15 and 45, respectively, in the *Electrical* Characteristics 6 Changed the MIN value for the ±2.3 mt B_{RP} parameter from –4 to –5 in the *Magnetic Characteristics* table 7 Changes from Revision * (March 2014) to Revision A (March 2014) Page Changed the type of the OUT terminal from OD to Output in the *Pin Functions* table4 Deleted Output pin current and changed V_{CC}max to V_{CC} after the voltage ramp rate for the supply voltage.... 5 Changed the MIN value for the ±2.3 mt B_{RP} parameter from +2.3 to -2.3 in the *Magnetic Characteristics* table Deleted condition statement from the *Typical Characteristics* and changed all T_J to T_A in the graph conditions8 Deleted Number from the Power-On Time case names; added conditions to captions of case timing diagrams Added the R1 tradeoff and lower current text after the equation in the Output Stage section13 Added the C2 not required for most applications text after the second equation in the Output Stage section....

13



Changed I_O to I_{SINK} in condition statement of FET overload fault condition in *Reverse Supply Protection*

5 Pin Configuration and Functions

For additional configuration information, see Device Markings and Mechanical, Packaging, and Orderable Information.

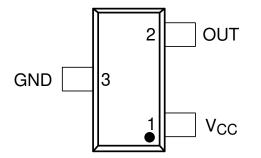


Figure 5-1. DBZ Package 3-Pin SOT-23 Top View

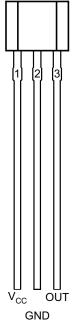


Figure 5-2. LPG and LPE Packages 3-Pin TO-92 **Top View**

Table 5-1. Pin Functions

PIN		TYPE	DESCRIPTION	
NAME	DBZ	LPG, LPE		DESCRIPTION
GND	3	2	Ground	Ground pin
OUT	2	3	Output	Hall sensor open-drain output. The open drain requires a resistor pullup.
V _{CC}	1	1	Power	2.5 V to 38 V power supply. Bypass this pin to the GND pin with a 0.01- μ F (minimum) ceramic capacitor rated for V _{CC} .

Product Folder Links: DRV5013



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
	V _{CC}	-22 ⁽²⁾	40	V
Power supply voltage	Voltage ramp rate (V _{CC}), V _{CC} < 5 V	Unlin	nited	V/µs
	Voltage ramp rate (V _{CC}), V _{CC} > 5 V	0	2	ν/μ5
Output pin voltage			40	V
Output pin reverse current during reverse supply condition			100	mA
Magnetic flux density, B _{MAX}		Unlin	nited	
Operating junction temperature T	Q, see Figure 9-1	-40	150	°C
Operating junction temperature, T _J	E, see Figure 9-1	-40	175	C
Storage temperature, T _{stg}			150	°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2500	\/
V _(ESD) discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±500	v	

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

				MIN	MAX	UNIT
V _{CC}	Power supply voltage	Power supply voltage		2.5	38	V
Vo	Output pin voltage (OUT	Output pin voltage (OUT)		0	38	V
I _{SINK}	Output pin current sink (Output pin current sink (OUT) ⁽¹⁾		0	30	mA
_	Operating ambient	Operating ambient Q, see Figure 9-1		-40	125	°C
temperature	E, see Figure 9-1		-40	150	C	

⁽¹⁾ Power dissipation and thermal limits must be observed.

6.4 Thermal Information

			DRV5013			
THERMAL METRIC(1)		DBZ (SOT-23)	LPG, LPE (TO-92)	UNIT		
		3 PINS	3 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	333.2	180	°C/W		
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	99.9	98.6	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	66.9	154.9	°C/W		
ΨЈТ	Junction-to-top characterization parameter	4.9	40	°C/W		
ΨЈВ	Junction-to-board characterization parameter	65.2	154.9	°C/W		

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

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⁽²⁾ Specified by design. Only tested to -20 V.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
POWER	SUPPLIES (V _{CC})						
V _{CC}	V _{CC} operating voltage		2.5		38	V	
1	Operating supply current	V _{CC} = 2.5 V to 38 V, T _A = 25°C		2.7		mA	
Icc	Operating supply current	$V_{CC} = 2.5 \text{ V to } 38 \text{ V}, T_A = T_{A, MAX}^{(1)}$		3	3.5	IIIA	
	Dower on time	AD, AG, BC versions		35	50		
t _{on} Power-on time		FA version		35	70	μs	
OPEN-DI	RAIN OUTPUT (OUT)						
_	FET on-resistance	V _{CC} = 3.3 V, I _O = 10 mA, T _A = 25°C		22		Ω	
r _{DS(on)}	FET OH-Tesistatice	$V_{CC} = 3.3 \text{ V}, I_{O} = 10 \text{ mA}, T_{A} = T_{A, MAX}$ (1)		36	50	12	
I _{lkg(off)}	Off-state leakage current	Output Hi-Z			1	μA	
PROTEC	TION CIRCUITS						
V _{CCR}	Reverse supply voltage		-22			V	
I _{OCP}	Overcurrent protection level	OUT shorted V _{CC}	15	30	45	mA	

⁽¹⁾ $T_{A, MAX}$ is 125°C for Q devices and 150°C for E devices (see Figure 9-1).

6.6 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
OPEN-DRA	AIN OUTPUT (OUT)					
t _d	Output delay time	B = B_{RP} – 10 mT to B_{OP} + 10 mT in 1 μ s		13	25	μs
t _r	Output rise time (10% to 90%)	R1 = 1 k Ω , C _O = 50 pF, V _{CC} = 3.3 V		200		ns
t _f	Output fall time (90% to 10%)	R1 = 1 k Ω , C _O = 50 pF, V _{CC} = 3.3 V		31		ns

Product Folder Links: DRV5013



6.7 Magnetic Characteristics

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT ⁽¹⁾
f_{BW}	Bandwidth ⁽²⁾		20	30		kHz
DRV501	13FA: ±1.3 mT		•			
B _{OP}	Operate point; see Figure 7-2		-0.6	1.3	3.4	mT
B _{RP}	Release point; see Figure 7-2	T = 40°C to T (1)	-3.4	-1.3	0.6	mT
B _{hys}	Hysteresis; $B_{hys} = (B_{OP} - B_{RP})$	$T_A = -40^{\circ}\text{C to } T_{A,MAX}^{(1)}$	1.2	2.6		mT
B _O	Magnetic offset; $B_O = (B_{OP} + B_{RP}) / 2$		-1.5	0	1.5	mT
DRV501	13AD: ±2.7 mT		•			
B _{OP}	Operate point; see Figure 7-2		1	2.7	5	mT
B _{RP}	Release point; see Figure 7-2	$T_A = -40^{\circ}\text{C to } T_{A,MAX}^{(1)}$	-5	-2.7	-1	mT
B _{hys}	Hysteresis; B _{hys} = (B _{OP} – B _{RP})	1A40 C to 1A,MAX(*)		5.4		mT
B _O	Magnetic offset; $B_O = (B_{OP} + B_{RP}) / 2$		-1.5	0	1.5	mT
DRV501	13AG: ±6 mT					
B _{OP}	Operate point; see Figure 7-2		3	6	9	mT
B _{RP}	Release point; see Figure 7-2	$T_A = -40^{\circ}\text{C to } T_{A,MAX}^{(1)}$	-9	-6	-3	mT
B _{hys}	Hysteresis; B _{hys} = (B _{OP} – B _{RP})	1A40 C to 1A,MAX(*)		12		mT
B _O	Magnetic offset; $B_O = (B_{OP} + B_{RP}) / 2$		-1.5	0	1.5	mT
DRV501	13BC: ±12 mT		•			
B _{OP}	Operate point; see Figure 7-2		6	12	18	mT
B _{RP}	Release point; see Figure 7-2	$T_A = -40^{\circ}\text{C to } T_{A,MAX}^{(1)}$	-18	-12	-6	mT
B _{hys}	Hysteresis; B _{hys} = (B _{OP} – B _{RP})	1A40 C to 1A,MAX(*)		24		mT
B _O	Magnetic offset; $B_O = (B_{OP} + B_{RP}) / 2$		-1.5	0	1.5	mT

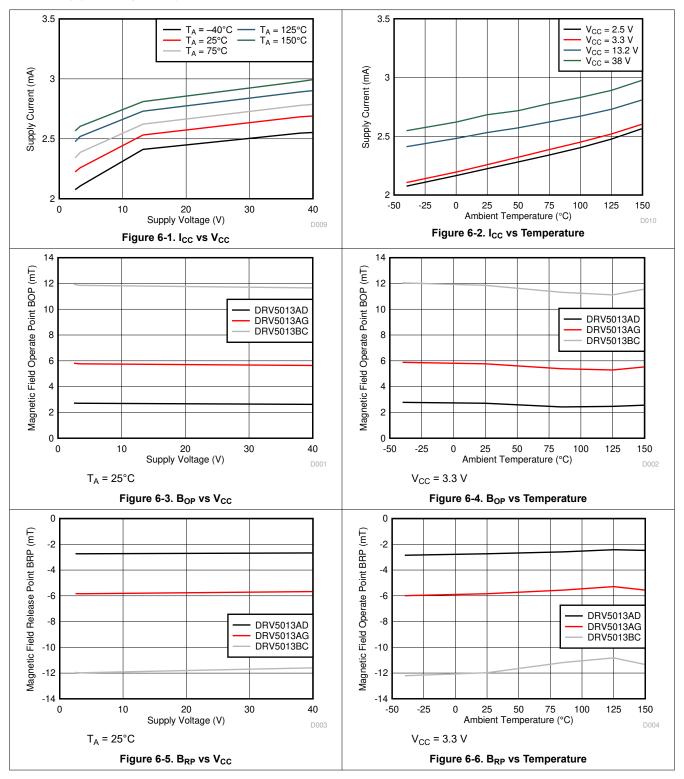
^{(1) 1} mT = 10 Gauss.

⁽²⁾ Bandwidth describes the fastest changing magnetic field that can be detected and translated to the output.



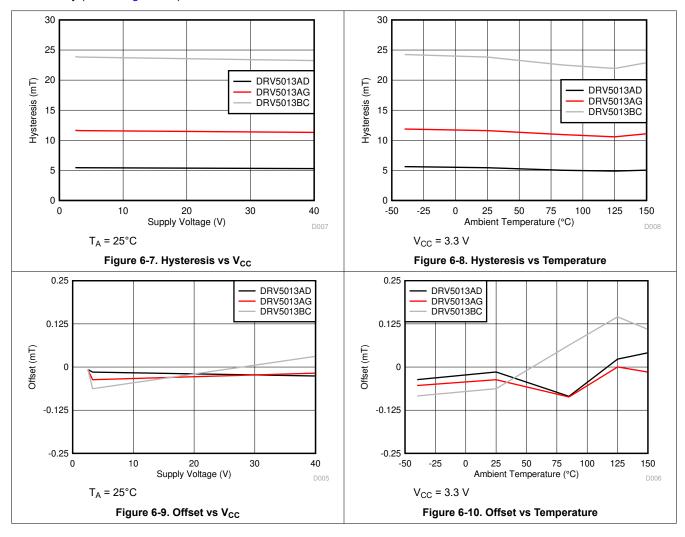
6.8 Typical Characteristics

 $T_A > 125$ °C data are valid for *E* temperature range devices only, see Figure 9-1 $T_A > 125$ °C data are valid for Grade 0 devices only (E, see Figure 9-1)



6.8 Typical Characteristics (continued)

 $T_A > 125$ °C data are valid for *E* temperature range devices only, see Figure 9-1 $T_A > 125$ °C data are valid for Grade 0 devices only (E, see Figure 9-1)





7 Detailed Description

7.1 Overview

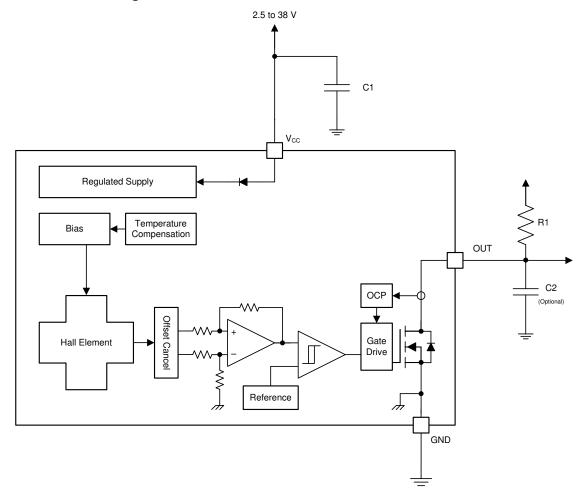
The DRV5013 device is a chopper-stabilized Hall sensor with a digital latched output for magnetic sensing applications. The DRV5013 device can be powered with a supply voltage between 2.5 V and 38 V, and continuously survives continuous -22 V reverse-battery conditions. The DRV5013 device does not operate when -22 V to 2.4 V is applied to the V_{CC} pin (with respect to the GND pin). In addition, the device can withstand voltages up to 40 V for transient durations.

The field polarity is defined as follows: a south pole near the marked side of the package is a positive magnetic field. A north pole near the marked side of the package is a negative magnetic field.

The output state is dependent on the magnetic field perpendicular to the package. A south pole near the marked side of the package causes the output to pull low (operate point, B_{OP}), and a north pole near the marked side of the package causes the output to release (release point, B_{RP}). Hysteresis is included in between the operate point and the release point therefore magnetic-field noise does not accidentally trip the output.

An external pullup resistor is required on the OUT pin. The OUT pin can be pulled up to V_{CC} , or to a different voltage supply. This allows for easier interfacing with controller circuits.

7.2 Functional Block Diagram



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7.3 Feature Description

7.3.1 Field Direction Definition

Figure 7-1 shows the positive magnetic field defined as a south pole near the marked side of the package.

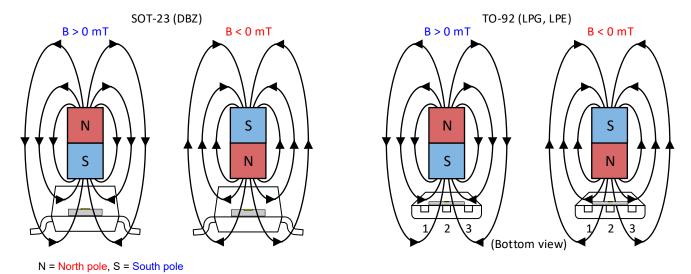


Figure 7-1. Field Direction Definition

7.3.2 Device Output

If the device is powered on with a magnetic field strength between B_{RP} and B_{OP} , then the device output is indeterminate and can either be Hi-Z or Low. If the field strength is greater than B_{OP} , then the output is pulled low. If the field strength is less than B_{RP} , then the output is released.

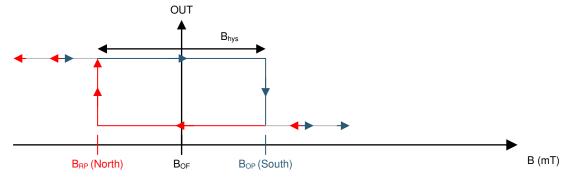


Figure 7-2. DRV5013 — $B_{OP} > 0$



7.3.3 Power-On Time

After applying V_{CC} to the DRV5013 device, t_{on} must elapse before the OUT pin is valid. During the power-up sequence, the output is Hi-Z. A pulse as shown in Figure 7-3 and Figure 7-4 occurs at the end of t_{on} . This pulse can allow the host processor to determine when the DRV5013 output is valid after start-up. In Case 1 (Figure 7-3) and Case 2 (Figure 7-4), the output is defined assuming a constant magnetic field $B > B_{OP}$ and $B < B_{RP}$.

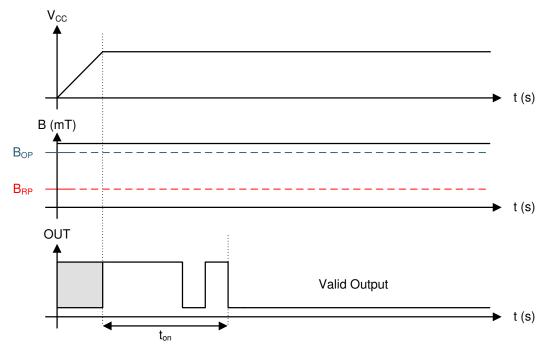


Figure 7-3. Case 1: Power On When B > B_{OP}

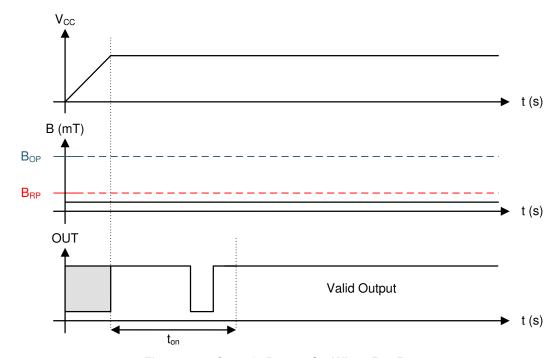


Figure 7-4. Case 2: Power On When B < B_{RP}

If the device is powered on with the magnetic field strength B_{RP} < B < B_{OP} , then the device output is indeterminate and can either be Hi-Z or pulled low. During the power-up sequence, the output is held Hi-Z

until t_{on} has elapsed. At the end of t_{on} , a pulse is given on the OUT pin to indicate that t_{on} has elapsed. After t_{on} , if the magnetic field changes such that $B_{OP} < B$, the output is released. Case 3 (Figure 7-5) and Case 4 (Figure 7-6) show examples of this behavior.

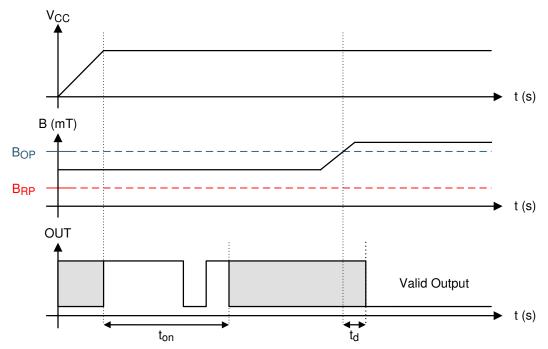


Figure 7-5. Case 3: Power On When $B_{RP} < B < B_{OP}$, Followed by $B > B_{OP}$

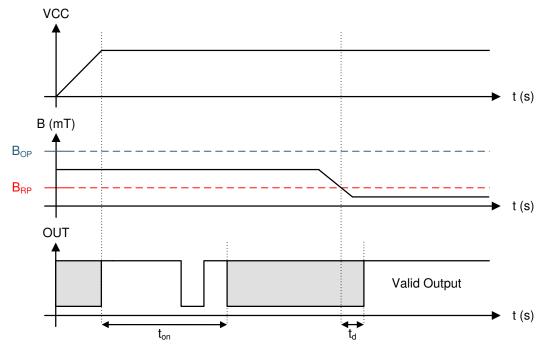


Figure 7-6. Case 4: Power On When $B_{RP} < B < B_{OP}$, Followed by $B < B_{RP}$

7.3.4 Output Stage

Figure 7-7 shows the DRV5013 open-drain NMOS output structure, rated to sink up to 30 mA of current. For proper operation, use Equation 1 to calculate the value of pullup resistor R1.



$$\frac{V_{ref} max}{30 mA} \le R1 \le \frac{V_{ref} min}{100 \mu A}$$
 (1)

The size of R1 is a tradeoff between the OUT rise time and the current when OUT is pulled low. A lower current is generally better, however faster transitions and bandwidth require a smaller resistor for faster switching.

In addition, make sure that the value of R1 > 500 Ω so that the output driver can pull the OUT pin close to GND.

Note

 V_{ref} is not restricted to V_{CC} . The allowable voltage range of this pin is specified in the *Absolute Maximum Ratings*.

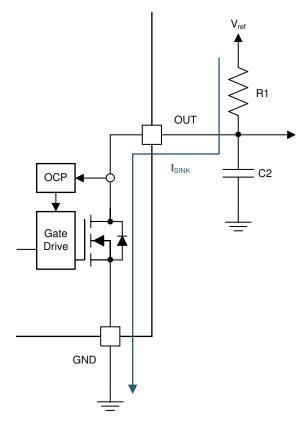


Figure 7-7. NMOS Open-Drain Output

Select a value for C2 based on the system bandwidth specifications as shown in Equation 2.

$$2 \times f_{\text{BW}} \text{ (Hz)} < \frac{1}{2\pi \times \text{R1} \times \text{C2}}$$
 (2)

Most applications do not require this C2 filtering capacitor.

7.3.5 Protection Circuits

The DRV5013 device is fully protected against overcurrent and reverse-supply conditions. Table 7-1 lists a summary of the protection circuits.

Table 7-1. Protection Circuit Summary

FAULT	CONDITION	DEVICE	DESCRIPTION	RECOVERY
FET overload (OCP)	I _{SINK} ≥ I _{OCP}	Operating	Output current is clamped to I _{OCP}	I _O < I _{OCP}
Load dump	38 V < V _{CC} < 40 V	Operating	Device will operate for a transient duration	V _{CC} ≤ 38 V
Reverse supply	-22 V < V _{CC} < 0 V	Disabled	Device will survive this condition	V _{CC} ≥ 2.5 V

7.3.5.1 Overcurrent Protection (OCP)

An analog current-limit circuit limits the current through the FET. The driver current is clamped to I_{OCP} . During this clamping, the $r_{DS(on)}$ of the output FET is increased from the nominal value.

7.3.5.2 Load Dump Protection

The DRV5013 device operates at DC V_{CC} conditions up to 38 V nominally, and can additionally withstand V_{CC} = 40 V. No current-limiting series resistor is required for this protection.

7.3.5.3 Reverse Supply Protection

The DRV5013 device is protected in the event that the V_{CC} pin and the GND pin are reversed (up to -22 V).

Note

In a reverse supply condition, the OUT pin reverse-current must not exceed the ratings specified in the *Absolute Maximum Ratings*.

7.4 Device Functional Modes

The DRV5013 device is active only when V_{CC} is between 2.5 V and 38 V.

When a reverse supply condition exists, the device is inactive.

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The DRV5013 device is used in magnetic-field sensing applications.

8.2 Typical Applications

8.2.1 Standard Circuit

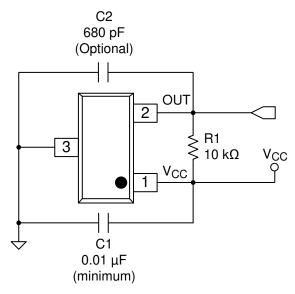


Figure 8-1. Typical Application Circuit

8.2.1.1 Design Requirements

For this design example, use the parameters listed in Table 8-1 as the input parameters.

Table 8-1. Design Parameters

DESIGN PARAMETER	REFERENCE	EXAMPLE VALUE
Supply voltage	V _{CC}	3.2 to 3.4 V
System bandwidth	f_{BW}	10 kHz

8.2.1.2 Detailed Design Procedure

Table 8-2. External Components

COMPONENT	PIN 1	PIN 2	RECOMMENDED
C1	V_{CC}	GND	A 0.01-μF (minimum) ceramic capacitor rated for V _{CC}
C2	OUT	GND	Optional: Place a ceramic capacitor to GND
R1	OUT	REF ⁽¹⁾	Requires a resistor pullup

⁽¹⁾ REF is not a pin on the DRV5013 device, but a REF supply-voltage pullup is required for the OUT pin; the OUT pin may be pulled up to V_{CC} .

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8.2.1.2.1 Configuration Example

In a 3.3-V system, 3.2 V \leq V_{ref} \leq 3.4 V. Use Equation 3 to calculate the allowable range for R1.

$$\frac{V_{ref} max}{30 mA} \le R1 \le \frac{V_{ref} min}{100 \mu A}$$
(3)

For this design example, use Equation 4 to calculate the allowable range of R1.

$$\frac{3.4 \text{ V}}{30 \text{ mA}} \le \text{R1} \le \frac{3.2 \text{ V}}{100 \text{ }\mu\text{A}}$$
 (4)

Therefore:

$$113 \Omega \le R1 \le 32 k\Omega \tag{5}$$

After finding the allowable range of R1 (Equation 5), select a value between 500 Ω and 32 k Ω for R1.

Assuming a system bandwidth of 10 kHz, use Equation 6 to calculate the value of C2.

$$2 \times f_{\text{BW}} \text{ (Hz)} < \frac{1}{2\pi \times \text{R1} \times \text{C2}}$$
 (6)

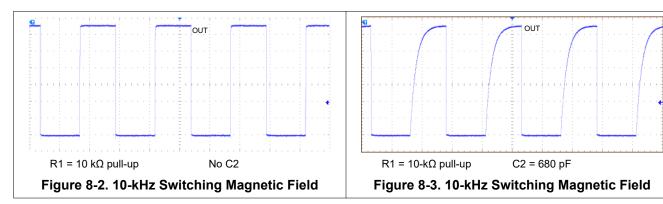
For this design example, use Equation 7 to calculate the value of C2.

$$2 \times 10 \text{ kHz} < \frac{1}{2\pi \times \text{R1} \times \text{C2}} \tag{7}$$

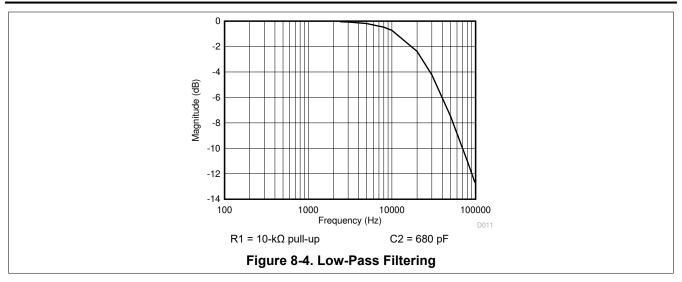
An R1 value of 10 $k\Omega$ and a C2 value less than 820 pF satisfy the requirement for a 10-kHz system bandwidth.

A selection of R1 = 10 k Ω and C2 = 680 pF would cause a low-pass filter with a corner frequency of 23.4 kHz.

8.2.1.3 Application Curves







8.2.2 Alternative Two-Wire Application

For systems that require minimal wire count, the device output can be connected to V_{CC} through a resistor, and the total supplied current can be sensed near the controller.

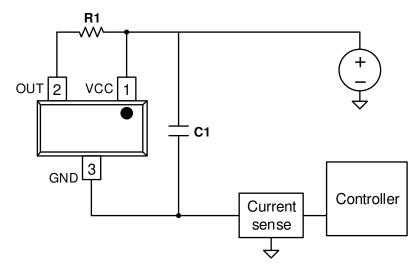


Figure 8-5. 2-Wire Application

Current can be sensed using a shunt resistor or other circuitry.

8.2.2.1 Design Requirements

Table 8-3 lists the related design parameters.

Table 8-3. Design Parameters

14510 0 01 2001911 1 41411101010								
DESIGN PARAMETER	REFERENCE	EXAMPLE VALUE						
Supply voltage	V _{CC}	12 V						
OUT resistor	R1	1 kΩ						
Bypass capacitor	C1	0.1 μF						
Current when B < B _{RP}	I _{RELEASE}	About 3 mA						
Current when B > B _{OP}	I _{OPERATE}	About 15 mA						

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8.2.2.2 Detailed Design Procedure

When the open-drain output of the device is high-impedance, current through the path equals the I_{CC} of the device (approximately 3 mA).

When the output pulls low, a parallel current path is added, equal to V_{CC} / (R1 + $r_{DS(on)}$). Using 12 V and 1 k Ω , the parallel current is approximately 12 mA, making the total current approximately 15 mA.

The local bypass capacitor C1 should be at least 0.1 μ F, and a larger value if there is high inductance in the power line interconnect.

8.3 Power Supply Recommendations

The DRV5013 device is designed to operate from an input voltage supply (VM) range between 2.5 V and 38 V. A $0.01-\mu F$ (minimum) ceramic capacitor rated for V_{CC} must be placed as close to the DRV5013 device as possible. Larger values of the bypass capacitor may be needed to attenuate any significant high-frequency ripple and noise components generated by the power source. TI recommends limiting the supply voltage variation to less than 50 mV_{PP}.

8.4 Layout

8.4.1 Layout Guidelines

The bypass capacitor should be placed near the DRV5013 device for efficient power delivery with minimal inductance. The external pullup resistor should be placed near the microcontroller input to provide the most stable voltage at the input; alternatively, an integrated pullup resistor within the GPIO of the microcontroller can be used.

Generally, using PCB copper planes underneath the DRV5013 device has no effect on magnetic flux, and does not interfere with device performance. This is because copper is not a ferromagnetic material. However, If nearby system components contain iron or nickel, they may redirect magnetic flux in unpredictable ways.

8.4.2 Layout Example

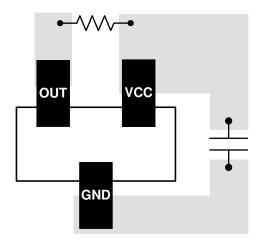


Figure 8-6. DRV5013 Layout Example



9 Device and Documentation Support

9.1 Device Support

9.1.1 Device Nomenclature

Figure 9-1 shows a legend for reading the complete device name for and DRV5013 device.

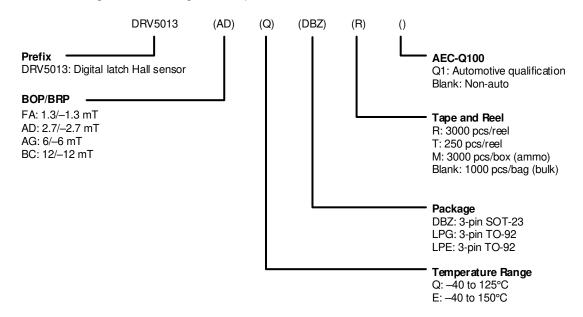
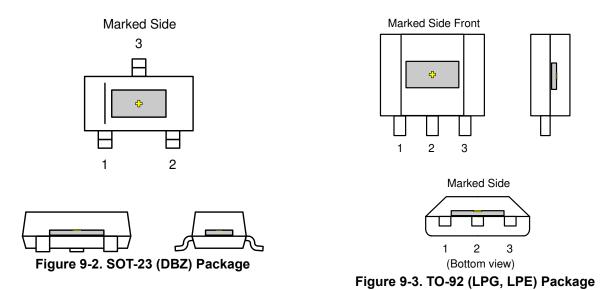


Figure 9-1. Device Nomenclature

9.1.2 Device Markings



9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

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9.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
DRV5013ADQDBZR	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	NIPDAUAG SN	Level-1-260C-UNLIM	-40 to 125	(+NLAD, 13AD, 1J52)	Samples
DRV5013ADQDBZT	ACTIVE	SOT-23	DBZ	3	250	RoHS & Green	NIPDAUAG SN	Level-1-260C-UNLIM	-40 to 125	(+NLAD, 13AD, 1J52)	Samples
DRV5013ADQLPG	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 125	+NLAD	Samples
DRV5013ADQLPGM	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 125	+NLAD	Samples
DRV5013AGQDBZR	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	NIPDAUAG SN	Level-1-260C-UNLIM	-40 to 125	(+NLAG, 13AG, 1IW2)	Samples
DRV5013AGQDBZT	ACTIVE	SOT-23	DBZ	3	250	RoHS & Green	NIPDAUAG SN	Level-1-260C-UNLIM	-40 to 125	(+NLAG, 13AG, 1IW2)	Samples
DRV5013AGQLPG	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 125	+NLAG	Samples
DRV5013AGQLPGM	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 125	+NLAG	Samples
DRV5013BCELPE	ACTIVE	TO-92	LPE	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	1UVJ	Samples
DRV5013BCELPEM	ACTIVE	TO-92	LPE	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 150	1UVJ	Samples
DRV5013BCQDBZR	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	NIPDAUAG SN	Level-1-260C-UNLIM	-40 to 125	(+NLBC, 1IX2)	Samples
DRV5013BCQDBZT	ACTIVE	SOT-23	DBZ	3	250	RoHS & Green	NIPDAUAG SN	Level-1-260C-UNLIM	-40 to 125	(+NLBC, 1IX2)	Samples
DRV5013BCQLPG	ACTIVE	TO-92	LPG	3	1000	RoHS & Green	SN	N / A for Pkg Type	-40 to 125	+NLBC	Samples
DRV5013BCQLPGM	ACTIVE	TO-92	LPG	3	3000	RoHS & Green	SN	N / A for Pkg Type	-40 to 125	+NLBC	Samples
DRV5013FAQDBZR	ACTIVE	SOT-23	DBZ	3	3000	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 125	(+NLFA, 1IZ2)	Samples

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available. **OBSOLETE:** TI has discontinued the production of the device.

PACKAGE OPTION ADDENDUM

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(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF DRV5013:

Automotive : DRV5013-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



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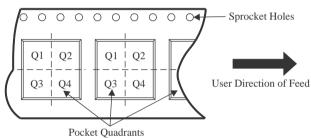
TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DRV5013ADQDBZR	SOT-23	DBZ	3	3000	180.0	8.4	3.2	2.85	1.3	4.0	8.0	Q3
DRV5013ADQDBZT	SOT-23	DBZ	3	250	180.0	8.4	3.2	2.85	1.3	4.0	8.0	Q3
DRV5013AGQDBZR	SOT-23	DBZ	3	3000	180.0	8.4	3.2	2.85	1.3	4.0	8.0	Q3
DRV5013AGQDBZT	SOT-23	DBZ	3	250	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3
DRV5013AGQDBZT	SOT-23	DBZ	3	250	178.0	9.0	3.15	2.77	1.22	4.0	8.0	Q3
DRV5013BCQDBZR	SOT-23	DBZ	3	3000	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3
DRV5013BCQDBZR	SOT-23	DBZ	3	3000	178.0	9.0	3.15	2.77	1.22	4.0	8.0	Q3
DRV5013BCQDBZT	SOT-23	DBZ	3	250	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3
DRV5013BCQDBZT	SOT-23	DBZ	3	250	178.0	9.0	3.15	2.77	1.22	4.0	8.0	Q3
DRV5013FAQDBZR	SOT-23	DBZ	3	3000	180.0	8.4	3.2	2.85	1.3	4.0	8.0	Q3
DRV5013FAQDBZR	SOT-23	DBZ	3	3000	180.0	8.4	3.15	2.77	1.22	4.0	8.0	Q3



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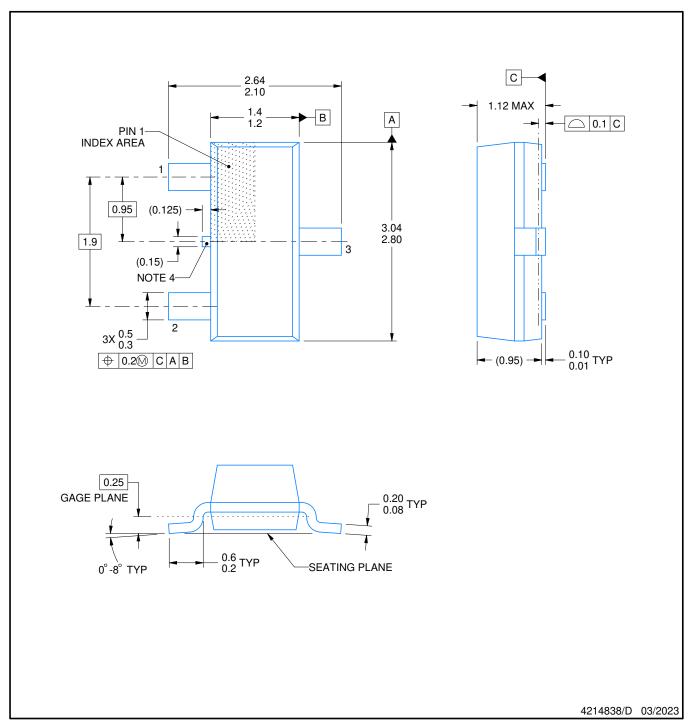


*All dimensions are nominal

7 til dilliciolorio die Homiliai							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DRV5013ADQDBZR	SOT-23	DBZ	3	3000	210.0	185.0	35.0
DRV5013ADQDBZT	SOT-23	DBZ	3	250	210.0	185.0	35.0
DRV5013AGQDBZR	SOT-23	DBZ	3	3000	210.0	185.0	35.0
DRV5013AGQDBZT	SOT-23	DBZ	3	250	202.0	201.0	28.0
DRV5013AGQDBZT	SOT-23	DBZ	3	250	180.0	180.0	18.0
DRV5013BCQDBZR	SOT-23	DBZ	3	3000	202.0	201.0	28.0
DRV5013BCQDBZR	SOT-23	DBZ	3	3000	180.0	180.0	18.0
DRV5013BCQDBZT	SOT-23	DBZ	3	250	202.0	201.0	28.0
DRV5013BCQDBZT	SOT-23	DBZ	3	250	180.0	180.0	18.0
DRV5013FAQDBZR	SOT-23	DBZ	3	3000	210.0	185.0	35.0
DRV5013FAQDBZR	SOT-23	DBZ	3	3000	202.0	201.0	28.0



SMALL OUTLINE TRANSISTOR

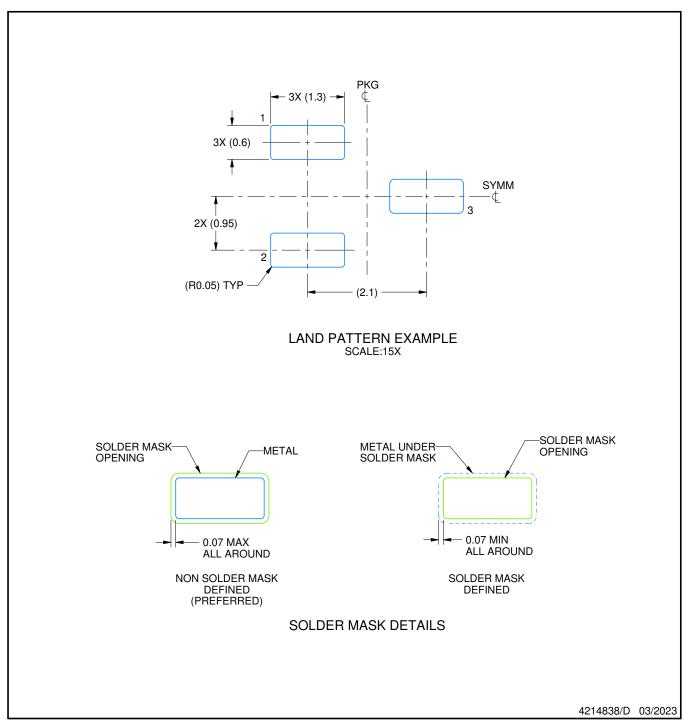


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.
 Reference JEDEC registration TO-236, except minimum foot length.
 Support pin may differ or may not be present.



SMALL OUTLINE TRANSISTOR

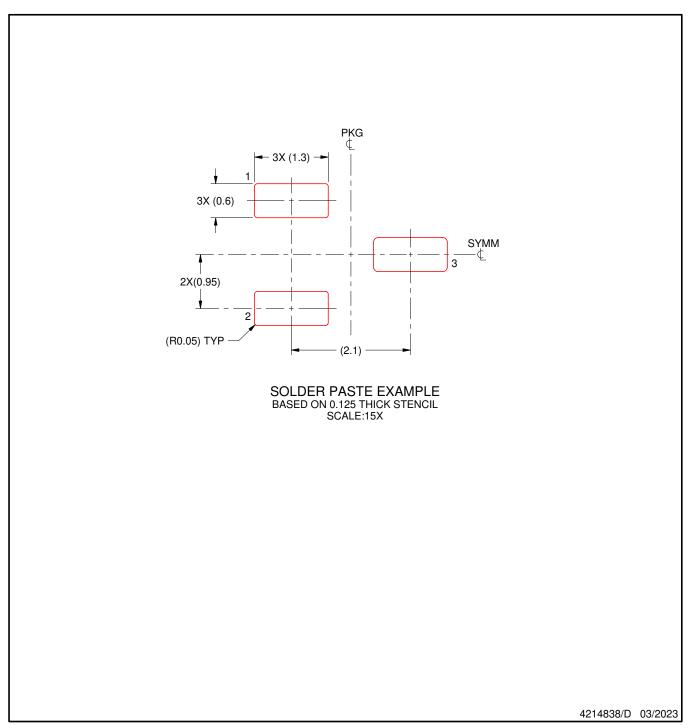


NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR

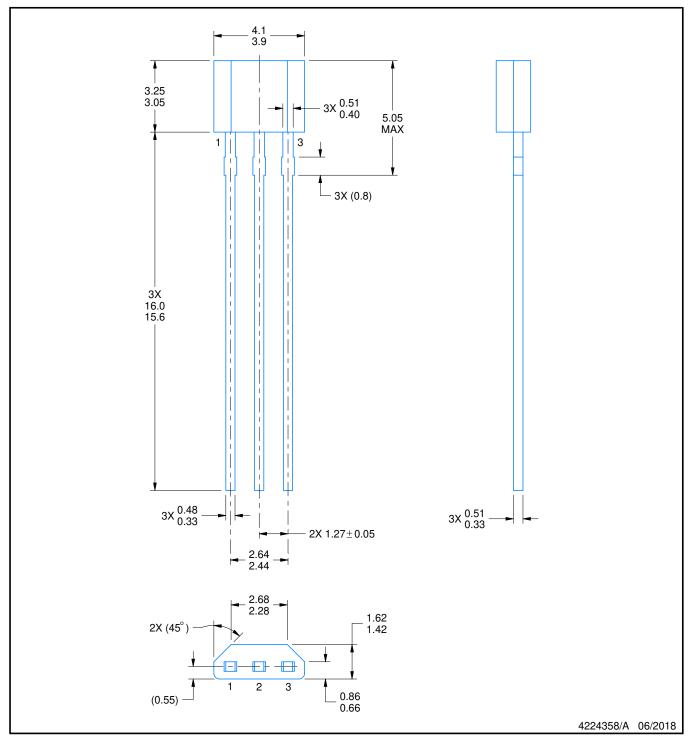


NOTES: (continued)

- 6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 7. Board assembly site may have different recommendations for stencil design.





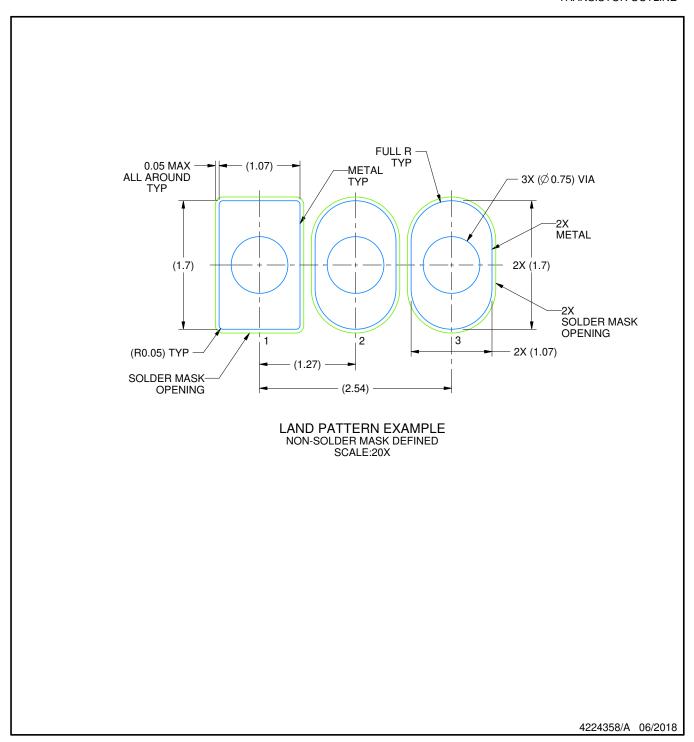


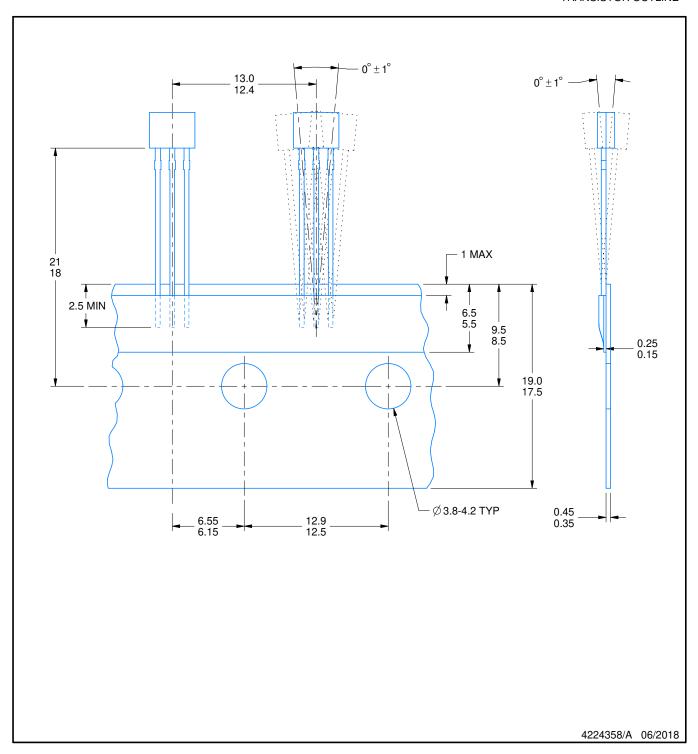
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

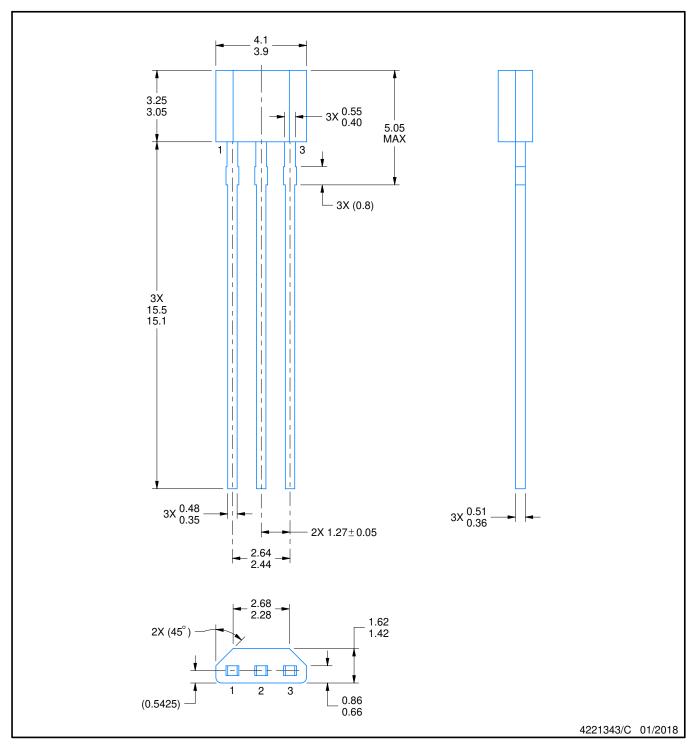
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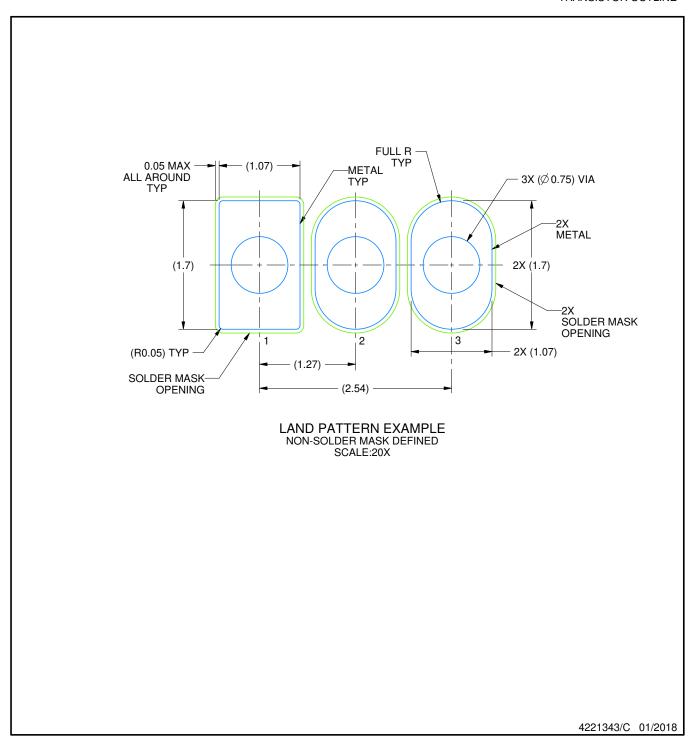


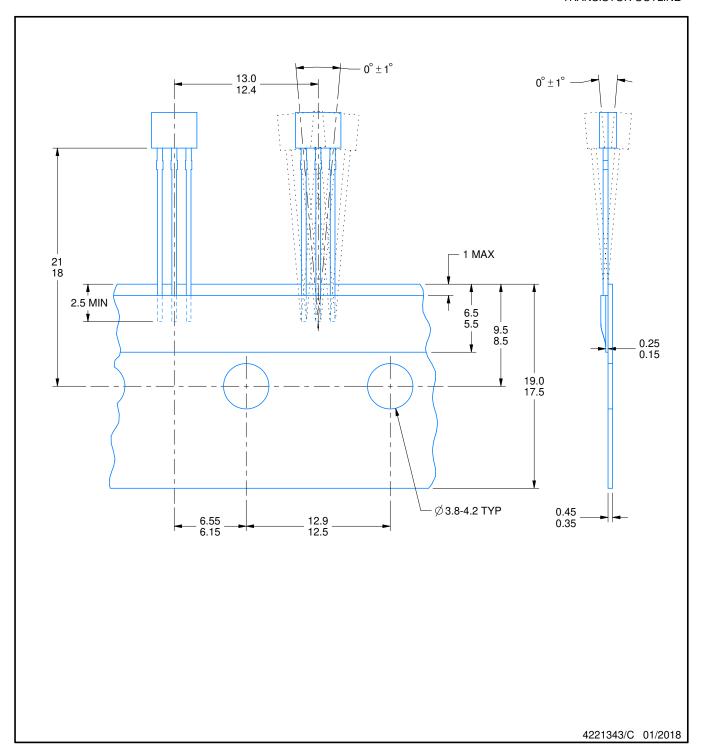
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